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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10082520	FILING DATE 02/22/2002	CLASS 356 438	SUBCLASS 11.630 2012	GAU 2012	EXAMINER Pham KESHAVAN
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354 505 plus

\*\*CONTINUING DATA VERIFIED: none

\*\* FOREIGN APPLICATIONS VERIFIED: yes  
JAPAN 2001-226984 07/27/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials <i>HP</i>		ATTORNEY DOCKET NO 16869P-041600US
TITLE : Method and apparatus for measuring thickness of thin film and device manufacturing method using same		

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O/G
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drawg.	Figs. Drawg. Print Fig.
<input type="checkbox"/> <b>TERMINAL</b>		Application Examiner	
<b>DISCLAIMER</b>		<b>PREPARED FOR ISSUE</b>	
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